



ARFTG

68th Microwave Measurement Conference

Measurement for Emerging Technologies

Omni Interlocken Resort, Broomfield, CO U.S.A. Nov. 28 – Dec. 1, 2006

www.arftg.org

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FIRST CALL FOR PAPERS

In conjunction with the ARFTG 2006 Short Course, ARFTG will hold its 68th Microwave Measurement Conference at the Omni Interlocken Resort in Broomfield, Colorado, November 30th to December 1st, 2006. Technical papers describing original work in the areas of microwave and millimeter wave measurement that support emerging technologies are solicited. Topics Include:

- THz Systems
- Nano (materials, devices, etc.)
- Multiport VNA Measurement
- Nonlinear Measurement
- High Speed Computer Systems Interconnect Measurement & Modeling
- Probing and fixturing
- Calibration Methods and Techniques
- Other areas of microwave and millimeter wave measurement.

DEADLINES

Sept. 8th, 2006 Electronic Abstract/Summary due to papersubmission@arftg.org

Oct. 13th, 2006 Publication-ready paper due in pdf format to papersubmission@arftg.org

Paper acceptance and classification will be communicated by **Sept. 22nd, 2006**. Information can be found in the Abstract/Summary Submission Instructions on our Web site, www.arftg.org

NIST/ARFTG MEASUREMENT SHORT COURSE

Join us in a practical microwave measurement tutorial. Day 1: Microwave measurements overview; circuit theory; VNA; interconnects and IC test fixtures and probing, RF connectors; on-wafer measurements; power; thermal noise; phase noise; Day 2: Possible topics include: uncertainty analysis; digital modulation; time-domain network analysis; overview of wireless test instrumentation and measurement; introduction to nonlinear measurements. Contact Dave Walker (dwalker@boulder.nist.gov) 303-497-5490 for more information.

NONLINEAR MEASUREMENT WORKSHOP

Many instruments used in nonlinear measurement are based on RF samplers, including oscilloscopes, LSNAs/MTAs, some VNAs and spectrum analyzers. We will discuss the advantages and weaknesses of high-frequency sampling compared to traditional RF mixing for measurements, especially in the case of large signals. Along with highlights on up-to-date very fast sampling technologies, we will discuss some more exotic techniques with surprising results and impressive capabilities. For more information, please contact Jean-Pierre Teyssier (teyssier@brive.unilim.fr).

EXHIBITS

The 68th ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information (jltauritz@ieee.org).

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